Se	earch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/680,878	XUE ET AL.
Examiner	Art Unit
Ly D. Pham	2827

SEARCHED				
Class	Subclass	Date	Examiner	
365	185.28, 185.18	3/23/2006	LP	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	DATE	EXMR
East update text search (see print- outs)	3/22/2006	LP
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